

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/520,439 MAYES ET AL.	
		Examiner	Art Unit ALEX NOGUEROLA	1795 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gopal et al. "Electrochemical Capacitance Voltage Profiling of the Narrow Band Gap Semiconductor InAs," Journal of Electronic Materials, vol. 29, No. 11, 2000
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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